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# INFORMATION DISCLOSURE STATEMENT BY APPLICANT

Applicant: OKUBO et al.

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Group Art Unit: 2826

Date: December 28, 2009

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## U.S. PATENT DOCUMENTS

Examiner's Initials*	Document Number	Date MM/YYYY	Name (Family Name of First Inventor)	Class	Sub Class	Filing Date (if appropriate)
	AR					
	BR					
	CR					
	DR					
	ER					
	FR					
	GR					
	HR					
	IR					
	JR					
	KR					
	LR					
	MR					
	NR					

## FOREIGN PATENT DOCUMENTS

	Document Number	Date MM/YYYY	Country	Inventor Name	English Abstract		Translation Readily Available	
					Enclosed	No	Enclose	No
/W.M./	OR	2000-329716 A	11-30-2000	Japan	KUSAKA TAKAO	X		
	PR							
	QR							
	RR							
	SR							
	TR							
	UR							
	VR							
	WR							
	XR							

## OTHER (Including in this order Author, Title, Periodical Name, Date, Pertinent Pages, etc.)

/W.M./	YR	"Kunio Takayanagi et al., "Semiconductor Measurement Evaluation Dictionary", Japan Science Forum Corporation, September 12, 1997, pages 87-90					X	
/W.M./	ZR	Notice of Reasons for Rejection for Japanese Application No. 2004-567897 dated November 4, 2009					X	
	AAR							
	BBR							

Examiner /Whitney Moore/

Date Considered: 12/29/2009

\*EXAMINER: Initial if citation considered, whether or not citation is in conformance with MPEP § 609. Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to Applicant.